

UNISONIC TECHNOLOGIES CO., LTD

11N50-CB Preliminary Power MOSFET

11A, 500V N-CHANNEL POWER MOSFET

■ DESCRIPTION

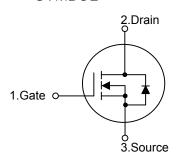
The **UTC 11N50-CB** is an N-channel enhancement mode power MOSFET. It uses UTC advanced planar stripe, DMOS technology to provide customers perfect switching performance, minimal on-state resistance. It also can withstand high energy pulse in the avalanche and commutation mode.

The **UTC 11N50-CB** is universally applied in electronic lamp ballasts based on half bridge topology, high efficiency switched mode power supplies, active power factor correction, etc.

■ FEATURES

- * $R_{DS(ON)}$ < 0.55 Ω @ V_{GS} = 10 V, I_{D} = 5.5 A
- * Fast Switching
- * With 100% Avalanche Tested

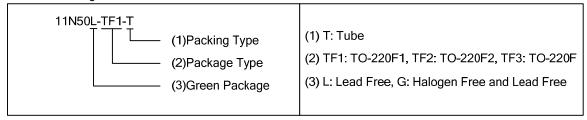
■ SYMBOL



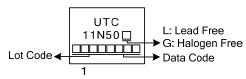
■ ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
11N50L-TF1-T	11N50G-TF1-T	TO-220F1	G	D	S	Tube	
11N50L-TF2-T	11N50G-TF2-T	TO-220F2	G	D	S	Tube	
11N50L-TF3-T	11N50G-TF3-T	TO-220F	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



■ MARKING



1 TO-220F

1 TO-220F1

TO-220F2

www.unisonic.com.tw 1 of 5

■ ABSOLUTE MAXIMUM RATINGS (T_C =25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain-Source Voltage		V _{DSS}	500	V	
Gate-Source Voltage		V_{GSS}	±30	V	
Drain Current	Continuous	I _D	11	Α	
	Pulsed (Note 2)	I _{DM}	44	Α	
Avalanche Current (Note 2)		I _{AR}	4.5	Α	
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	101	mJ	
Peak Diode Recovery dv/dt (Note 4)		dv/dt	3.9	V/ns	
Power Dissipation		P_D	48	W	
Junction Temperature		T_J	150	°C	
Storage Temperature Range		T _{STG}	-55 ~ +150	°C	

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L=10mH, I_{AS} =4.5A, V_{DD} = 50V, R_{G} =25 Ω , Starting T_{J} =25 $^{\circ}$ C
- 4. $I_{SD} \le 11A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATING	UNIT	
Junction to Ambient	θ_{JA}	62.5	°C/W	
Junction to Case	$\theta_{ m JC}$	2.6	°C/W	

■ ELECTRICAL CHARACTERISTICS (T_J =25°C, unless otherwise specified)

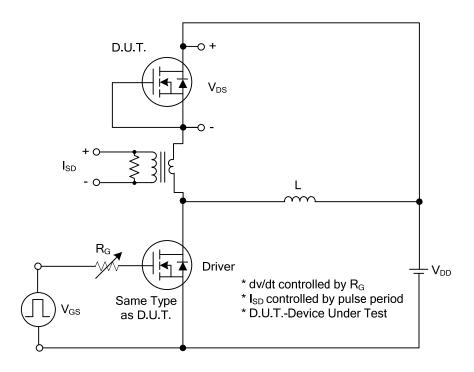
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
OFF CHARACTERISTICS								
Drain-Source Breakdown Voltage	BV _{DSS}	V_{GS} =0 V , I_D =250 μ A	500			V		
Drain-Source Leakage Current	I _{DSS}	V _{DS} =500V, V _{GS} =0V			10	μΑ		
Cata Source Leakage Current Forward		V_{DS} =0 V , V_{GS} =±30 V			±100	nA		
Gate-Source Leakage Current Reverse	I_{GSS}	V_{GS} =-30V, V_{DS} =0V			-100	nA		
ON CHARACTERISTICS								
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	2.0		4.0	V		
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =5.5A			0.55	Ω		
DYNAMIC PARAMETERS								
Input Capacitance	C _{ISS}			1690		pF		
Output Capacitance	Coss	V_{GS} =0V, V_{DS} =25V, f=1.0MHz		150		pF		
Reverse Transfer Capacitance	C _{RSS}			130		pF		
SWITCHING PARAMETERS								
Total Gate Charge (Note 1)	\mathbf{Q}_{G}	 V _{DS} =50V, V _{GS} =10V, I _D =1.3A ,		37		nC		
Gate to Source Charge	Q _{GS}	I _G =100μA (Note 1, 2)		6		nC		
Gate to Drain Charge	Q_GD	IG-100μΑ (Note 1, 2)		7		nC		
Turn-ON Delay Time (Note 1)	t _{D(ON)}			73		ns		
Rise Time	t _R	V_{DD} =30V, V_{GS} =10V, I_{D} =0.5A,		45		ns		
Turn-OFF Delay Time	t _{D(OFF)}	R _G =25Ω (Note 1, 2)		250		ns		
Fall-Time	t _F			50		ns		
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS								
Maximum Body-Diode Continuous Current	Is				11	Α		
Maximum Body-Diode Pulsed Current	I _{SM}				44	Α		
Drain-Source Diode Forward Voltage (Note 1)	V_{SD}	I _S =11A, V _{GS} =0V			1.4	V		
Body Diode Reverse Recovery Time (Note 1)	t _{rr}	I _S =11A, V _{GS} =0V,		310		ns		
Body Diode Reverse Recovery Charge	Qrr	dI _F /dt=100A/μs		2.23		μC		

Notes: 1. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2%.

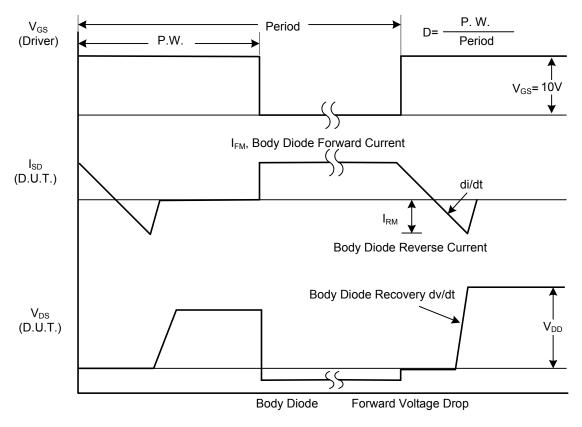
^{2.} Essentially independent of operating temperature.



■ TEST CIRCUITS AND WAVEFORMS

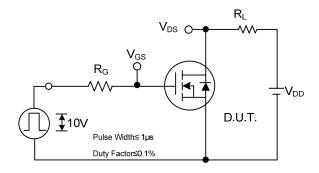


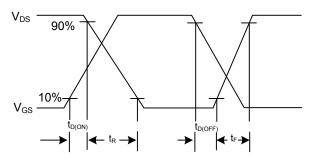
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

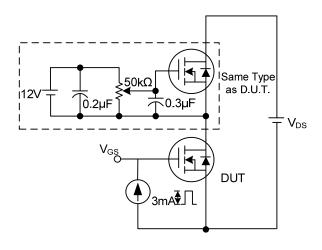
■ TEST CIRCUITS AND WAVEFORMS (Cont.)

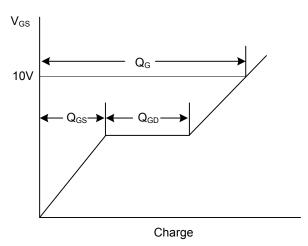




Switching Test Circuit

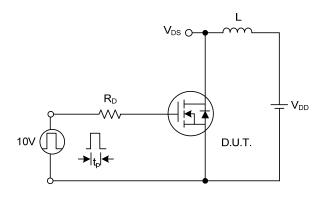
Switching Waveforms

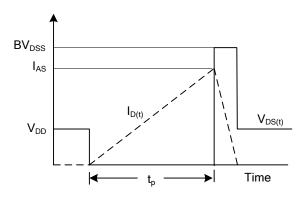




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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